



ARFTG 57TH Microwave Measurements Conference: Best Practice and Strategies for RF Test

IEEE MTT-S IMS2001, Phoenix, Arizona · May 25, 2001

FINAL CALL FOR PAPERS

In conjunction with the IEEE MTT-S International Microwave Symposium (IMS), the Automatic RF Techniques Group will hold its 57th Conference in Phoenix on May 25, 2001.

The main ARFTG program is entitled, "Best Practice and Strategies for RF Test." The conference will focus on current issues in measurement technology and metrology as best applied by industry:

- What level of accuracy do customers need in their measurements?
- What are the best system measurements and what do the specs say?
- How do we keep the cost-of-test down while meeting those specs?
- What constitutes weakly nonlinear versus truly large-signal behavior and how do we tailor the testing?
- How do we qualify a completely integrated wireless system?

Papers on metrology (e.g., accuracy, equipment selection, test methodology, etc.) and practical measurement aspects (e.g., cost of test, cost of equipment, speed of test, etc.) are encouraged. Original papers on all topics, including general microwave metrology and nonlinear/large-signal measurement, are also welcomed.

Special presentations relevant to the conference theme will include Dr. Stavros Iezekiel of the University of Leeds discussing lightwave S-parameter measurements, John Mahan of M/A-Com on practical test considerations in a production microwave component manufactory, and Eric Strid of Cascade Microtech on high-throughput probe-based microwave measurements.

DEADLINES

February 16	Electronic Abstract/Summary due to David Walker
March 16	Publication-ready paper due in pdf format to David Walker

Paper acceptance and classification will be communicated by March 2. If your paper is accepted, you are invited to submit to the Special Symposium Issue of IEEE MTT.

INSTRUCTIONS FOR AUTHORS

Contributed papers will be presented as 20-minute talks or in an interactive poster session, and published in both the 57th ARFTG Digest and the 2001 International Microwave Symposium CD-ROM. You can express a preference for an interactive poster session.

We request that authors submit a one-page abstract and a 500-1000 word summary, including illustrations, to allow for evaluation with regard to the interests of the participants and the quality and novelty of the work. Please make your submission electronically to the Technical Program Chair following the *Abstracts/Summary Submission Instructions* found on the web site, www.arftg.org.

EXHIBITS

The 57th ARFTG Conference also offers an outstanding exhibition opportunity. Please contact our Exhibits Chair directly for further information.

Conference Chair

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